

Notice of References Cited	Application/Control No. 10/754,701	Applicant(s)/Patent Under Reexamination SEMICONDUCTOR ENERGY LAB	
	Examiner DAO H. NGUYEN	Art Unit 2818	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,684,365	11-1997	Tang et al.	315/169.3
	B	US-			
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	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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